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To Examiner: Jack S.J. Chen Technology Center 2800	Total Pages Sent: 10 (including cover sheet)
Facsimile Number: (703) 872-9306	Transmission Date: January 24, 2005

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicant:	Tews, <i>et al.</i>	Docket No.:	00P9031US
Serial No:	09/714,356	Art Unit:	2813
Date Filed:	November 16, 2000		
Title:	Nitrogen Implantation Using a Shadow Effect to Control Gate Oxide Thickness in DRAM Semiconductor		

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- Response to Restriction (9 pages)

Respectfully submitted,

  
Kristin Hayes  
Legal Assistant

Confirmation Respectfully Requested

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## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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CENTRAL FAX CENTERApplicants: Tews, *et al.*

Docket No.: 00P9031US

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Serial No.: 09/714,356

Art Unit: 2813

Filed: November 16, 2000

Examiner: Chen, Jack S.J.

For: Nitrogen Implantation Using a Shadow Effect to Control Gate Oxide Thickness in  
DRAM SemiconductorMail Stop Amendment  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450**RESPONSE TO RESTRICTION**

Dear Sir:

Applicant has received and reviewed the Office Action mailed on January 11, 2005 and respectfully requests reconsideration based on the following remarks.

00P9031US

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